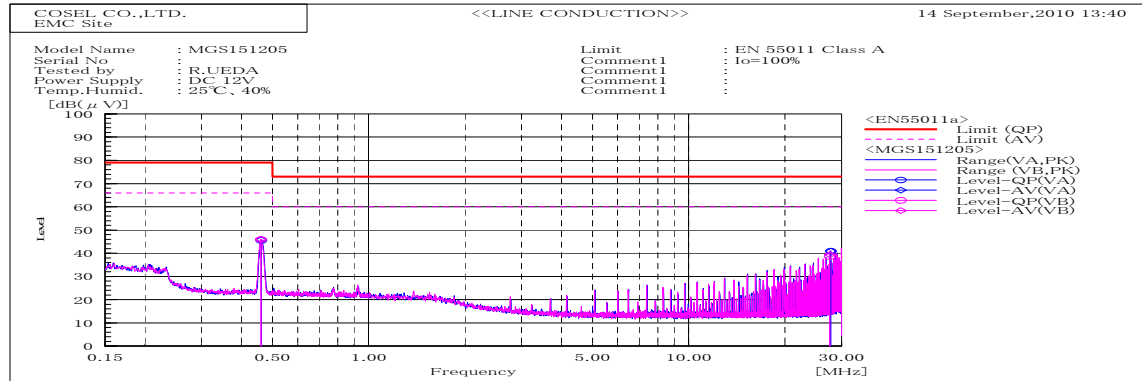
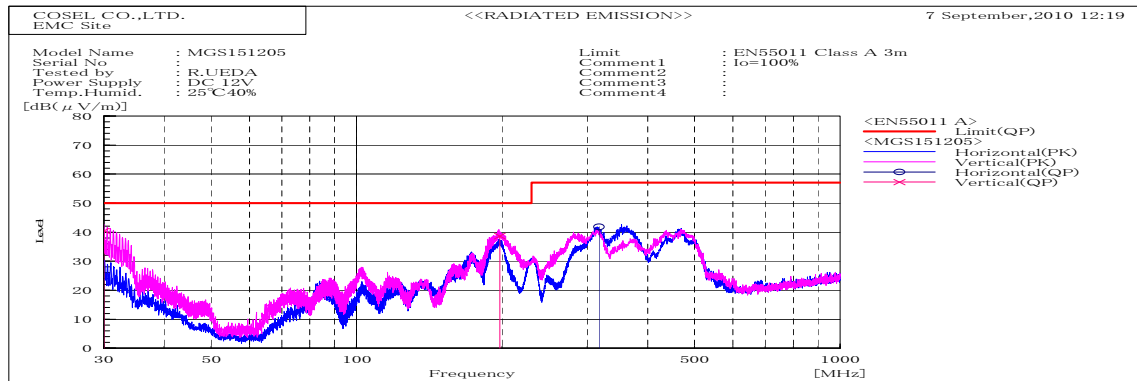


DATA SHEET		Date	21-Sep-10
Model	MGS151205	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Ueda



Frequency MHz	Harm	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.46032		VB	35.9	36.1	10	45.9	46.1	79	66	33.1	19.9	Pass	
0.46144		VA	35.4	35.7	10.1	45.5	45.8	79	66	33.5	20.2	Pass	
27.5831		VB	27.6	28.4	11	38.6	39.4	73	60	34.4	20.6	Pass	
27.79655		VA	30.2	30.2	10.7	40.9	40.9	73	60	32.1	19.1	Pass	

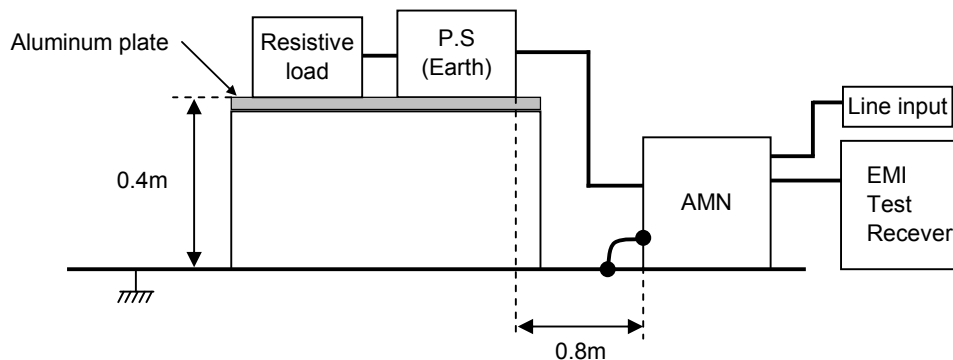


Frequency MHz	Polarization	Stability	Reading dB(uV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV						
30.032	V	Stable	53.8	-13.4		40.4		50	9.6	Pass	139	317	
197.749	V	Stable	60.7	-22		38.7		50	11.3	Pass	130	230	
317.217	H	Stable	59	-17.2		41.8		57	15.2	Pass	133	172	

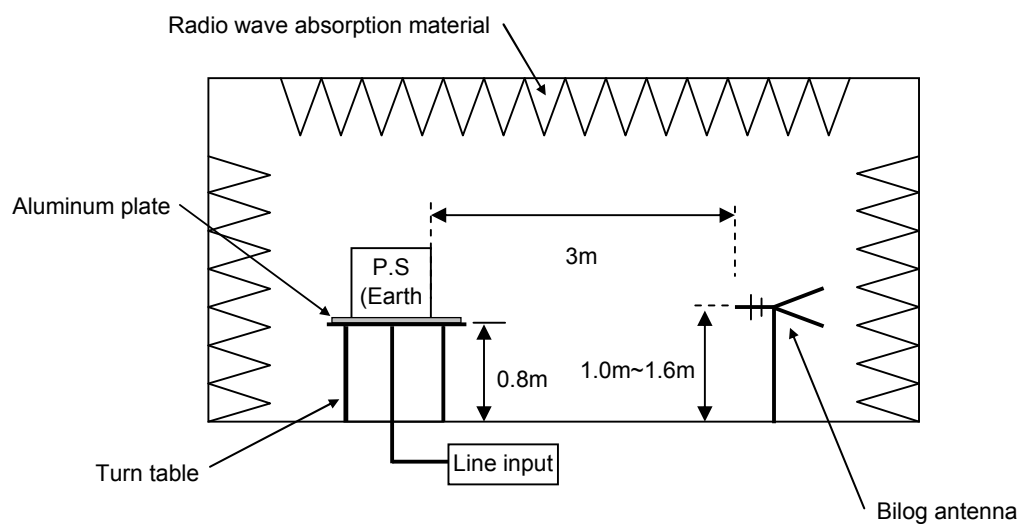
DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

1. Line conduction



2. Radiated emission



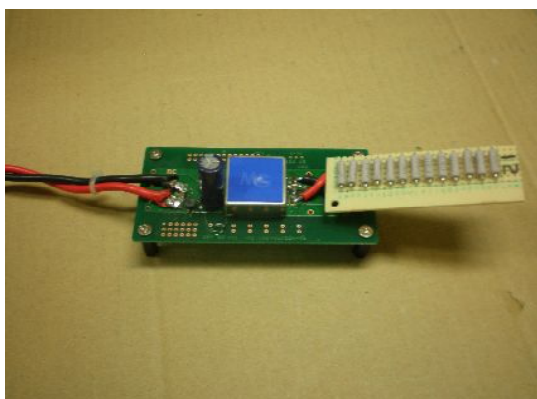


Conditions

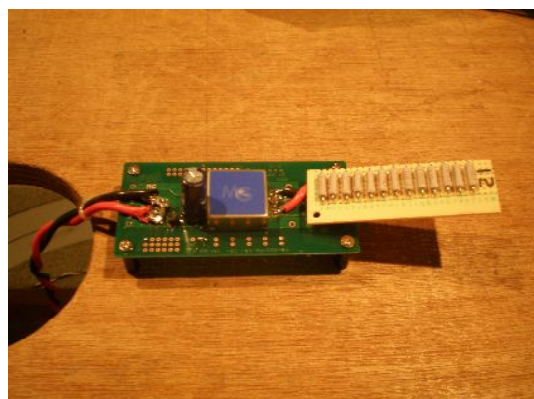
Test : EMI
Model Name : MGS1512□□/MGW1512□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

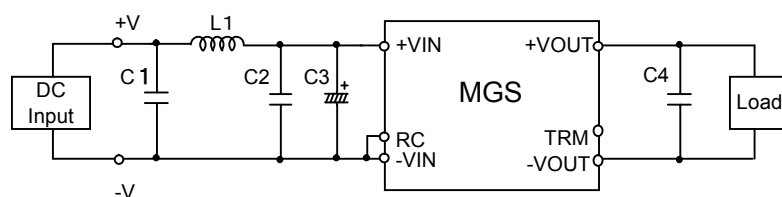


Fig.1 Testing circuitry 1

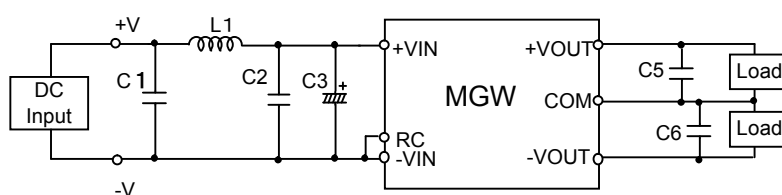


Fig.2 Testing circuitry 2

L1	: 0.5 μ H	CI4C-0R5	(KORIN ELECTRONICS)
C1,C2	: 25V 10 μ F	CM316X5R106K25A	(KYOCERA)
C3	: 50V 220 μ F	LXY50VB220M	(NIPPON CHEMI-CON)
C4,C5,C6	: 25V 22 μ F	CM32X5R226K25A	(KYOCERA)